Art Unit 2192			Application/Control No.		Api	Applicant(s)/Patent under Reexamination	ent under Rec	examination	
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(Date) PRIMARY EXAMINER  Hoang-Vu Antony Nguyen-Ba 10/11/06  (Date) (Primary Examiner) (Date) 10/11/06	NONE		Mondowantenton		ANTONY NG	SUYEN-BA	Total	Claims Allo	owed:
Hoang-Vu Antony Nguyen-Ba 10/11/06 (Date) (Primary Examiner) (Date)		Date)		<i>\</i>	PRIMARY E	XAMINER		13	
(Date) (Primary Examiner)			Hoang-Vu Antony Nguyen-		9		O.G. Print Clair		O.G. Print Figure
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